Cybersecurity in the Next-Generation Industrial Internet of Things Era: Modelling, Detecting and Mitigating Threats

Guest Editors:

Dr. Panagiotis Radoglou-Grammatikis

Dr. Panagiotis Sarigiannidis

Dr. Thomas Lagkas

Prof. Dr. Vasileios Argyriou

Deadline for manuscript submissions:
closed (30 September 2022)

Message from the Guest Editors

This Special Issue will cover a wide range of IIoT cybersecurity and privacy solutions, combining a plethora of emerging technologies. Researchers are invited to submit novel contributions in, but not limited to, the following topics:

- Cybersecurity analysis of IIoT communication protocols; Privacy issues and solutions in IIoT communication protocols;
- Threat modelling and vulnerability assessment in IIoT ecosystems;
- SDN/NFV-based cybersecurity architectures for IIoT ecosystems;
- AI-based intrusion mitigation and prevention solutions for IIoT ecosystems;
- SDN-based intrusion mitigation and prevention solutions for IIoT ecosystems;
- Security information and event management systems for IIoT ecosystems;
- Trust management in IIoT ecosystems, Cybersecurity deception mechanisms in IIoT ecosystems;
- Blockchain-based authentication and access control systems for IIoT ecosystems;
- Self-healing cybersecurity mechanisms in IIoT ecosystems;
- Privacy-preserving tools, frameworks and schemes in IIoT ecosystems;
- Cyber threat intelligence management and sharing in IIoT ecosystems.

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Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

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